## Supporting Information

## Controlled Growth of Large-scale Uniform 1T' MoTe<sub>2</sub> Crystals

## with Tunable Thickness and Its Photodetector Application

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Structure and composition Characterization: Optical images are taken on an Olympus

BX51 microscope. AFM is done on a Bruker ICON microscope. XPS analysis is done on an Axis Ultra system. TEM imaging was performed on a probe aberration-corrected JEM-2100F operated at 200 kV. Normal Raman are measured on a Renishaw in Via micro-Raman spectroscope with 532 nm laser. Angle-resolved polarization Raman spectra are achieved with a half-wave being used to turn the polarization angle of excitation laser. The angular optical contrast spectrum is obtained using a Witec RSA300+ confocal optical microscope equipped with a  $100 \times$  objective (N.A.= 0.9). The angle-resolved optical contrast is performed with polarized light from a KL 1500 halogen lamp (Zeiss) by rotating the samples. Angle -resolved polarized optical image is captured by adding a polarizer in the light path of the optical microscope.

Device Fabrication and Electrical Measurement: The few-layer 1T' MoTe<sub>2</sub> Crystal devices are fabricated by electron-beam lithography and physical mask with Cu grid, and the contact metal of Cr/Au (5/50 nm) electrodes are fabricated by thermal evaporation deposition. The measurement is carried out in a probe station and measured by Keithley 2614b semiconductor analyzer under ambient air at room temperature. Wavelength-dependent photo-response of the devices are performed under the 532 nm, 950 nm, and 1550 nm laser (power: 50 mW; focusing at the interface region with a diameter of  $\approx 2$  mm) excitation. Temperature-dependent  $I_{ds}$ - $V_{ds}$  curves are performed on a heating stage.

*Density-functional ab initial molecular dynamics (AIMD) simulations*: The density-functional ab initial molecular dynamics (AIMD)<sup>[1]</sup> simulations have been performed on all structures by using the Vienna Ab initio simulation (VASP)<sup>[2]</sup> package, implemented with the generalized gradient approximation (GGA)<sup>[3]</sup>. All calculations employed Γ-point sampling of the Brillouin zone. In the present AIMD simulations, *NVT* canonical ensemble was performed by integrating the equations of motion at 1 fs time intervals, and controlling temperature via a Nosé-Hoover thermostat that the temperature ranges from 300 to 1100 K with a step of 200 K. At each of time step, the total energy was convergent to an accuracy of  $10^{-4}$  eV/atom using a plane-wave energy cutoff of 400 eV. The total simulation time was 3000 ps at every temperature. The

atomic-scale AIMD  $4 \times 4 \times 1$  supercell model of 1T' MoTe<sub>2</sub> nanoribbons with 96 atoms are constructed.



**Figure S1**. Compared experimental result for normal and modified CVD growth of 1T' MoTe<sub>2</sub>. (a) The photograph of substrate for 1T' MoTe<sub>2</sub> growth with (right) and without (left) molecular sieve assistant. (b-d) Optical images of normal CVD growth of 1T' MoTe<sub>2</sub> in large scale, center and the edge of substrate, respectively. (e-g) Optical images of modified CVD growth of 1T' MoTe<sub>2</sub> in large scale, center and the edge of substrate, respectively. (e-g) Optical images of substrate, respectively.



Figure S2. XPS full spectrum of single crystal 1T' MoTe<sub>2</sub> on SiO<sub>2</sub>/Si substrate.



**Figure S3**. (a) Optical microscopy image of transfered monolayer, bilayer and trilayer of 1T' MoTe<sub>2</sub> on SiO<sub>2</sub>/Si substrate with 300 thickness oxide layer. (b) Raman spectra of 1T' MoTe<sub>2</sub> in different layers. (c) The relationship between the optical contrast of R, G, and B channels of 1T' MoTe<sub>2</sub> and layer numbers on 300 nm SiO<sub>2</sub>/Si. (d) A selected sample of 1T' MoTe<sub>2</sub> with a special morphology. (e,f) Raman spectra and the G value of optical contrast at three positions in Figure S3d.



Figure S4. (a-b) AFM images of monolayer (a), bilayer (b-c) 1T' MoTe<sub>2</sub> crystal are obtained at 650 °C, 700 °C, and 750 °C, respectively.

Table S1: Figure-of-merit of	photosensing	devices based on some	other typical 2D materials
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Materials	Spectral range[nm]	R [AW <sup>-1</sup> ]	Response time [ms]	Ref.
GaS	254-610	19.2	≤30	4
MoS <sub>2</sub>	300-800	1.96	98	5
WSe <sub>2</sub>	500-900	1.8×10 <sup>5</sup>	5×10 <sup>3</sup>	6
InSe	370–980	27	500	7
GaSe	254-610	2.8	20	8
In <sub>2</sub> Se <sub>3</sub>	254-1064	20.5	24.6	9
BP	400–940	4.8×10 <sup>-3</sup>	1	10
2H MoTe <sub>2</sub>	600-1750	0.05	1.6	11
Thick 1T'	522 10600	0.4×10-3	4 <b>2</b> 5×10-3	12
MoTe <sub>2</sub>	332-10000	0.4×10 5	42.3×10 <sup>3</sup>	
Few layer	532 1550	0.83	5×10 <sup>3</sup>	This work
1T' MoTe <sub>2</sub>	352-1350	0.83	3×10 <sup>5</sup>	THIS WOLK

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